

Diffractive Optical Element (DOE) & Microstructure Component

Abstract



Diffractive optical elements (DOEs) and micro structured surfaces enable a hugh variety of optical functions, such as beam splitters, beam shapers and diffusers. Due to the diffractive approach, these elements are usually thinner and lighter than most refractive elements, while providing unique and powerful options for many applications in optics. In this Use Case, we demonstrate how such components can be defined in VirtualLab Fusion using the Microstructureand Diffractive Optical Element (DOE) components.

Where to find the Components?



The Diffractive Optical Element (DOE) component and the Microstructure component can be found under Components > Single Surface & Stack.

Both components use the same internal solver and only have different names for the ease of recognition and application. In this Use Case we will show the *Microstructure* component, but everything can analogously be applied to the *Diffractive Optical Element (DOE)* component.

Function of the Microstructure Component

For the propagation of light through a desired microstructure, the *Microstructure Component* applies a *Complex Surface Response* – meaning a response function for amplitude and phase for all field components – to the impinging light. This response function can be either defined directly as a transmission function or can be calculated for a given height profile by applying *Thin Element Approximation* (TEA).



 n_2

 n_1

Base Interface

On the Solid tab, general parameters are defined, such as the media behind the particular surface, where the intended structure is located. The user can utilize an extended library of different materials to choose from or define own materials using dispersion formulas e.g. Sellmeier-Equation.



Definition as Complex Surface Response

On the *Channel Operator* tab, the Complex Surface Response of the desired DOE can be defined either by setting a complex transmission function...



T 1: Transmission

Data View

Definition as Stack – Real Height Profile

OK

Cancel

Help

Stacks Catalog ... or by configuring the real height profile in a so-Block Definition Type LightTrans Defined V called Stack. × Filter by ... - Single Gratings Base Metagrating Pillar Grating Programmable Grating Rectangular Grating Sampled Grating Sawtooth Grating Sinusoidal Grating Index z-Distance z-Position lanted Grating Edit Microstructure Component × 0 mm 0 mm Slanted Grating With Rounded Edg Tansition Point List Grating 2 1 µm 1 µm Solid Channel Operator riangular Grating Volume Grating Operator Specified by ... O Complex Surface Response Stack Coordinate Systems Grating Stack



If the microstructure is defined by a *Stack*, the user can use predefined templates from our catalogues, including different grating types as well as sampled or programmable structures to configure the intended height profile.

X

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Structure

Fourier Transforms

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\$ Channel

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Orientation of the Microstructure

Edit Microstructure Component X			
Coordinate Systems Position / Orientation Structure Channel Configuration $F F^{-1}$ Fourier Transforms	Solid Channel Operator Operator Specified by O Complex Surface Response Stack Grating Stack Sampled Grating Con Dack Side of Base Surface On Back Side of Base Surface Method for Stack Analysis Parabasal Thin Element Approximation Accuracy Factor 1 1 1		
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The orientation of the *Stack* can be specified to either be applied on the front side of the surface (defined in the Solid tab) or on its back side. Please note that the stack will be rotated by 180 degrees if positioned on front side, what influences the internal coordinate system of the used *Stack* and needs to be considered during the definition of the height profile, eventually.

Applied Solver

Edit Microstructure Component X		
Solid Channel Operator Operator Specified by O Complex Surface Response Stack Grating Stack		
Sampled Grating Image: Constraint of Base Surface Position / On Front Side of Base Surface		
Orientation Method for Stack Analysis Parabasal Thin Element Approximation Accuracy Factor Thin Element Approximation		
Structure Channel Configuration		
Validity:		

The component offers two solvering algorithms, namely (paraxial) *Thin Element Approximation* and *Parabasal Thin Element Approximation*.

The first solver assumes the incident light is perpendicular to the underlying *Plane Surface* (defined in the Solid tab). For the parabasal solver, the local direction of the incident light is considered in addition by using linear phase fitting algorithms.



Accuracy Factor

Edit Microstructure Component		
Edit Microstructure	Solid Channel Operator Operator Specified by O Complex Surface Response Stack Grating Stack Sampled Grating Coal Clip Coll On Front Side of Base Surface O On Back Side of Base Surface Method for Stack Analysis Parabasal Thin Element Approximation Accuracy Factor 1 1 1	×
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The Accuracy Factor enables the control of the number of sampling points, which will be used to resolve the shape of the defined height profile during the analysis by *TEA*. Especially in case of complex height profiles it may be necessary to increase this value in order to consider the microstructure accurately.

As the *Microstructure Component* only defines the surface where the microstructure is located, for configuring an element on a substrate a back surface is necessary. This can be achieved by adding a *Plane Surface* under *Components > Single Surface & Coating* and configuring the proper distance (thickness of substrate) and material.



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